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Advances in Fault Detection/Diagnosis of Electrical Power Devices

Guest Editors:

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Deadline for manuscript submissions:

closed (31 March 2023)

Message from the Guest Editors

Reliability-oriented fault detection and fault-tolerant control are state-of-the-art research trends that demand further intensive research in order to obtain applicable cost-effective technology. This motivates the aim of this Special Issue of Electronics. Accordingly, I cordially invite researchers to contribute original and unique articles, as well as review papers. The topics of interest include (with emphasis on electrical power devices), but are not limited to:

- condition monitoring
- cyber-attack detection
- cyber-physical systems
- data-driven approaches including machine learning methods
- electrical power devices
- fault detection and diagnosis
- fault ride through
- fault-tolerant control
- incipient faults
- observer design
- signal-based approaches for features extraction











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Editor-in-Chief

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Message from the Editor-in-Chief

Electronics is a multidisciplinary journal designed to appeal to a diverse audience of research scientists, practitioners, and developers in academia and industry. The journal is devoted to fast publication of latest technological breakthroughs, cutting-edge developments, and timely reviews of current and emerging technologies related to the broad field of electronics. Experimental and theoretical results are published as regular peer-reviewed articles or as articles within Special Issues guest-edited by leading experts in selected topics of interest.

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